

Jacobson Holman

Professional Limited Liability Company 400 Seventh Street, N.W. Washington, D.C. 20004-2218 (202) 638-6666 (202) 393-5350/51/52 (fax) www.jhip.com Firm e-mail: ip@jhip.com

YOON S. HAM
Direct: (202)662-8483
yham@jhip.com

July 8, 2003

Honorable Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Atty.Docket No.: <u>P68974US0</u>
CUSTOMER NUMBER: 00136

Sir:

Transmitted herewith for filing is the patent application in the name of:

Jae Sung CHOI of Cheongjoo-Shi, Republic of Korea,

for **METHOD OF FORMING DUAL DAMASCENE PATTERN IN SEMICONDUCTOR DEVICE.** The application comprises a $\underline{13}$ -page specification including $\underline{7}$ claims (1 independent) and Abstract, $\underline{3}$ sheets of drawings (Figs. 1A-2F), and a Declaration and Power of Attorney.

Also accompanying this application for filing is:

- (1) Assignment document, cover sheet and \$40.00 fee for recordation of Assignment.
- (2) Information Disclosure Statement, Form PTO-1449 and copies of references; and
- (3) A certified copy of **Korean** Application No. **2002-82661**, filed **December 23, 2002**, the priority of which is claimed under 35 U.S.C. §119.

The filing fee has been calculated as shown:

Large Entity \$ 750.00 Total Claims= $\underline{7}$; in excess of 20 = 0 x (\$18.00) = Total Ind. Claims= $\underline{1}$; in excess of 03 = 0 x (\$84.00) = + TOTAL FILING FEE: \$ 750.00

A check in the amount of \$790.00, is enclosed to cover the Total Filing Fee and an Assignment Recordation Fee. The Commissioner is hereby authorized to charge payment of any fees set forth in Sections 1.16 or 1.17 during the pendency of this application, or credit any overpayment, to deposit Account No. 06-1358. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

Yoon S. Ham Reg. No. 45,307

YSH: kyc

Enclosures
Harvey B. Jacobson, Jr. John Clarke Holman Simor L. Moskowitz Allen S. Melser Michael R. Slobasky Marsha G. Gentner Jonathan L. Schere Irwin M. Aisenberg George W. Lewis William E. Player Yoon S. Ham Philip L. O'Neill

1. KN 20, 851